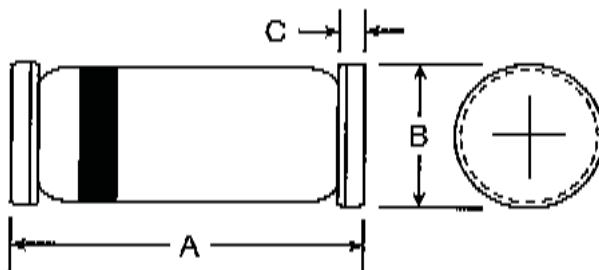


■ FEATURES

- Voltage range 100 Volts
- Surge overload ratings to 2 amperes peak
- Ideal for printed circuit board
- Reliable low cost construction utilizing molded plastic technique results in inexpensive product
- Terminal : Pure tin plated lead free,
- Mounting position: Any

■ MECHANICAL DATA

- Case: Mini MELF
- Terminals: Solderable per MIL-STD-202, Method 208
- Polarity: Cathode Band
- Marking: Cathode Band Only
- Weight: 0.05 grams (approx)



MINI-MELF		
Dim	Min	Max
A	3.30	3.70
B	1.30	1.60
C	0.28	0.50

All Dimensions in mm

MINI-MELF(LL-34)
Dimensions in inches and (millimeters)

■ MAXIMUM RATINGS & ELECTRICAL CHARACTERISTICS

Rating at 25°C ambient temperature unless otherwise specified. Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%

Parameter	Symbol	LL4148		Unit
Maximum Repetitive Peak Reverse Voltage	V _{RRM}	100		V
Maximum RMS Voltage	V _{RMS}	75		V
Forward Repetitive Peak Current (Note 1)	I _{FSM}	500		mA
Forward DC current at Ta=25°C	I _F	200		mA
Maximum Average Forward Current	I _{F(AV)}	150		mA
Peak Forward Surge Current tp=1uS	I _{FSM}	2.0		A
Typical Resistance Junction to Amvient Air (Note 1)	R _{θJA}	350		K/W
Operating and Storage Temperature Range	T _{J, T_{STG}}	-65 to +175		°C

Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Forward Voltage I _F =5.0mA I _F = 50mA	V _F	0.62	0.72 1.00	V
Peak Reverse Current V _R =20V V _R =20V, T _j =150°C V _R =75V	I _R	—	25 50 5.0	nA uA uA
Reverse Recovery Time (Note 2)	t _{rr}	—	4.0	nS

NOTE: 1. Valid Provided that Terminals are Kept at Ambient Temperature.

2. Reverse Recovery Test Conditions: I_F=10mA, V_R=6V, I_{rr}=0.1 x I_R, R_L=100Ω

■ RATING & CHARACTERISTIC CURVES

FIG.1-MAXIMUM NON-REPETITIVE FORWARD SURGE CURRENT

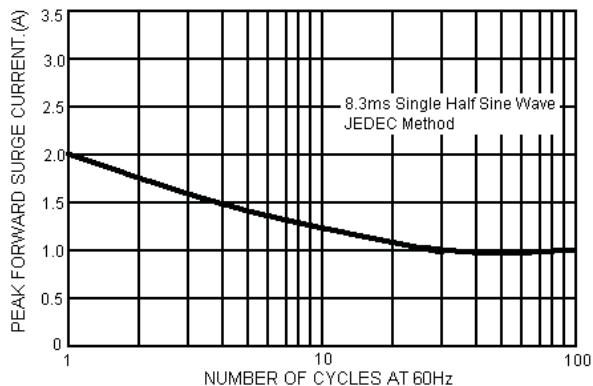


FIG.2-MAXIMUM FORWARD CURRENT DERATING

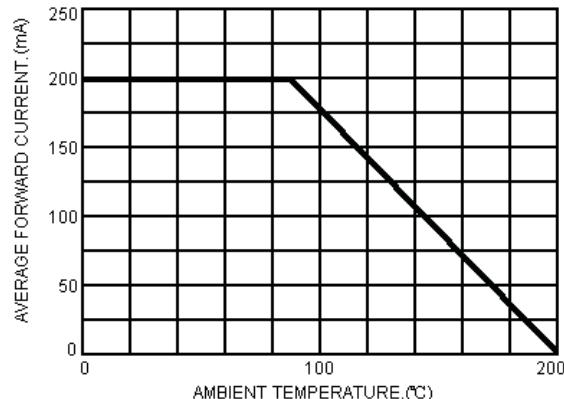


FIG.3-TYPICAL INSTANTANEOUS FORWARD CHARACTERISTICS

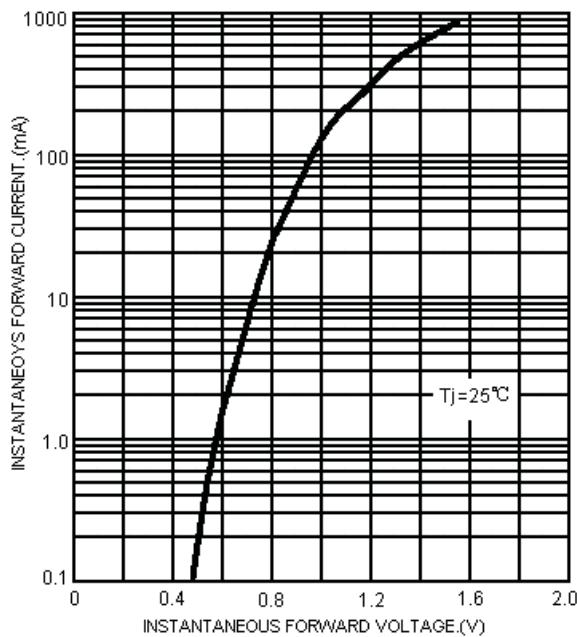


FIG.4-TYPICAL REVERSE CHARACTERISTICS

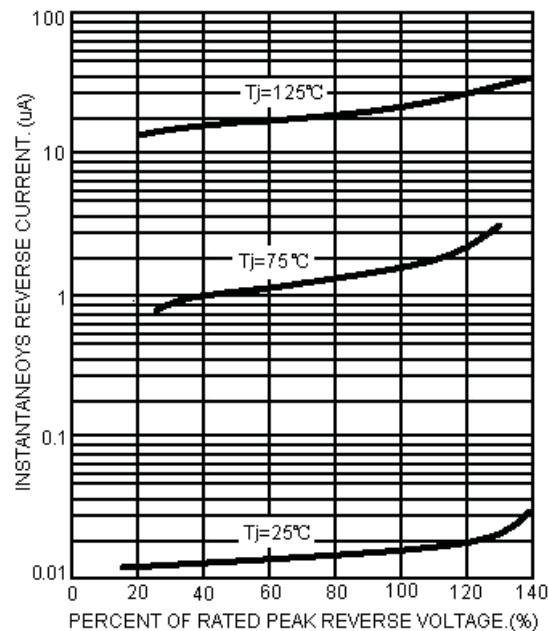


FIG.5-REVERSE RECOVER TIME CHARACTERISTIC AND TEST CIRCUIT DIAGRAM

